



FOR IMMEDIATE RELEASE

Contacts:

Aehr Test Systems

Gary Larson
Chief Financial Officer
(510) 623-9400 x321

MKR Group Inc.

Todd Kehrli or Jim Byers
Analyst/Investor Contact
(323) 468-2300
aehr@mk-group.com

**Aehr Test Systems to Announce First Quarter Fiscal 2015 Financial Results
on September 30, 2014**

Fremont, CA (September 16, 2014) – Aehr Test Systems (NASDAQ: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, today announced that it will report financial results for its fiscal 2015 first quarter ended August 31, 2014 on Tuesday, September 30, 2014 following the close of the market. The Company will host a conference call and webcast at 5:00 p.m. Eastern time that afternoon to discuss the results.

What: Aehr Test Systems first quarter fiscal 2015 financial results conference call

When: Tuesday, September 30th at 5:00 p.m. Eastern Time (2:00 p.m. PT)

Dial in Number: To access the live call, dial **888-455-2296** (US and Canada) or **719-325-2144** (International) and give the participant passcode **5777388**.

Webcast: To access the live webcast, please visit the investor relations section at www.aehr.com.

Call Replay: A phone replay of the call will be available approximately two hours following the end of the call through 8:00 p.m. ET on Tuesday, October 7, 2014.

Replay Numbers: **888-203-1112** (US and Canada)
719-457-0820 (International)
Replay passcode: **5777388#**

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS™ and FOX™ families of test and burn-in systems and the DiePak® carrier. The ABTS system is used in production and qualification testing of packaged parts for both lower-power and higher-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

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